

LISTING OF CLAIMS:

Claims 1 – 13 (Canceled)

14. (Currently Amended) Method for measuring the geometry and surface evenness of one side of a first moving metal strip and for measuring the geometry and surface evenness of one side of a second moving metal strip comprising:

providing a moving first metal strip having a surface to be measured;

providing a light source and a transparency between said light source and said ~~metal strip~~ surface of said first metal strip;

producing a pattern on the ~~metal strip~~ surface of the first metal strip to be measured using said light source, wherein said light source ~~can produces~~ produces a changeable first pattern on the ~~metal~~ surface of the first metal strip with the aid of said transparency,

viewing the pattern on said ~~metal strip~~ surface of said first metal strip with a camera; and

determining the geometry and surface evenness of said ~~metal strip~~ surface of said first metal strip;

providing a moving second metal strip having a surface to be measured;

providing said light source and said transparency between said light source and said surface of said second metal strip;

producing a pattern on the surface of the second metal strip to be measured using said light source, wherein said light source produces a second pattern on the surface of the second metal strip with the aid of said transparency, viewing the pattern on said surface of said second metal strip with a camera; and

determining the geometry and surface evenness of said second metal strip.

15. (Currently Amended) Method according to claim 14, comprising producing said first and second pattern with the aid of a liquid-crystal device.

16. (Previously Amended) Method according to claim 14, comprising filtering elastic form changes using the initially detected peaks and separating the peaks according to different frequencies and wavelength on account of strip movements.

17. (Previously Amended) Method according to claim 14, comprising determining said geometry by using the edge boundary of the strip.

18. (Previously Amended) Method according to claim 17, wherein the strip width or cut length is determined from the edge boundary.

19. (Previously Amended) Method according to claim 14, further comprising measuring the geometry of a known element of a measuring device and generating by computation a reference plane and a reference phase image from said measured geometry.

20. (Currently Amended) Method ~~for measuring the geometry and surface evenness of one side of a moving metal strip~~ according to claim 14, further comprising:

~~providing a moving metal strip having a surface to be measured;~~

~~providing a~~ disposing said light source disposed above said moving metal strip and emitting light from said light source;

delivering said light through a said transparency onto said metal surface[;],

therein producing said pattern by means of projection; and

~~producing a pattern on the metal surface to be measured using a light source, wherein the pattern on said one side of the metal surface to be measured is produced by means of projection with the aid of said transparency;~~

filtering elastic form changes using the initially detected peaks and separating the peaks according to different frequencies and wavelength on account of strip movements; and
~~viewing the pattern formed on said metal surface evenness with a camera.~~

21. (Currently Amended) Method ~~for measuring the geometry and surface evenness of one side of a moving metal strip~~ according to claim 14, further comprising:

~~providing a moving metal strip having a surface to be measured;~~
~~providing a disposing said light source disposed above said moving metal strip and emitting light from said light source;~~
~~delivering said light through a said transparency onto said metal surface[;],~~
~~therein producing said pattern by means of projection; and~~
~~producing a pattern on that one side of the metal strip to be measured using a light source wherein the pattern on the metal surface to be measured is produced by means of projection with the aid of said transparency;~~
~~viewing said formed pattern with a camera; and~~
~~determining said strip geometry and surface evenness by using the edge boundary of said strip.~~

22. (Previously presented) Method according to claim 21, characterized in that the strip width or cut length is determined from the edge boundary.

23. (Currently Amended) Method ~~for measuring the geometry and surface evenness of one side of a moving metal strip~~ according to claim 14, further comprising:

~~providing a moving metal strip having a surface to be measured;~~

~~providing a disposing said light source disposed above said moving metal strip and emitting light from said light source;~~
~~delivering said light through a said transparency only onto said metal surface[;],~~
~~therein producing said pattern by means of projection;~~
~~producing a pattern on that one side of the metal surface to be measured using a light source wherein the pattern on the metal surface to be measured is produced by means of projection with the aid of said transparency, viewing said formed pattern with a camera measuring the geometry of a known element of a measuring device and generating by computation a reference plane and a reference phase image from said measured geometry; and~~
~~comparing said pattern produced on said strip to said reference phase image.~~

24. (Previously Presented) Method according to claim 14, characterized in that a line pattern is produced on the metal surface.

25 – 27. (Canceled)